

AMENDMENTS TO THE CLAIMS

1. (Currently Amended) A quality assurance automatic display system comprising:
a data processor having an inspection item data hold section and a data processing section;
the inspection item data hold section holding inspection item graded data for a plurality of inspection items which have been graded by determination of reliability for each of the inspection items ~~of a per inspection item~~ for a substance to be inspected; and
the data processing section determining general graded data pertaining to the degree of quality assurance of the substance in accordance with an algorithm employed in the data processing section after having received the inspection item graded data from the inspection item data hold section, wherein the general graded data corresponds to weighted inspection item graded data for each substance inspected; and
a display device for displaying, for an individual semiconductor device that has been inspected, the general graded data transported from the data processing section, thereby indicating the degree of quality assurance of the inspected individual semiconductor device.

2. (Original) The quality assurance automatic display system according to claim 1, wherein the data processor further comprises an inspection data hold section for holding inspection data pertaining to the substance for each of the inspection items, and the general graded data are determined in the data processing section on the basis of both the inspection item graded data and the inspection data transported from the inspection data hold section.

3. (Original) The quality assurance automatic display system according to claim 1, wherein the inspection item graded data are produced as a result of a determination being made by means of taking, as references, an inspection apparatus and an inspection method corresponding to the inspection item.

4. (Original) The quality assurance automatic display system according to claim 1, wherein the display device is a printer which prints the general graded data directly onto the substance.

5. (Original) The quality assurance automatic display system according to claim 1, wherein the substance to be inspected corresponds to a semiconductor device, a photomask, or photomask indirect material.

6. (Original) The quality assurance automatic display system according to claim 1, wherein the substance to be inspected is a photomask, and the display device is constructed so as to provide the general graded data on an area within a pattern region on the photomask in which no pattern is to be formed.